

Fuel retention in high energy ion damaged tungsten

M.J. Simmonds, M.J. Baldwin, R.P. Doerner, G.R. Tynan

Center for Energy Research, UC San Diego, 9500 Gilman Dr., La Jolla, CA 92093-0417, USA







PISCES

Motivation

• Current understanding of H retention in high energy ion damage

- Research gaps that need to be addressed
 - Synergisms

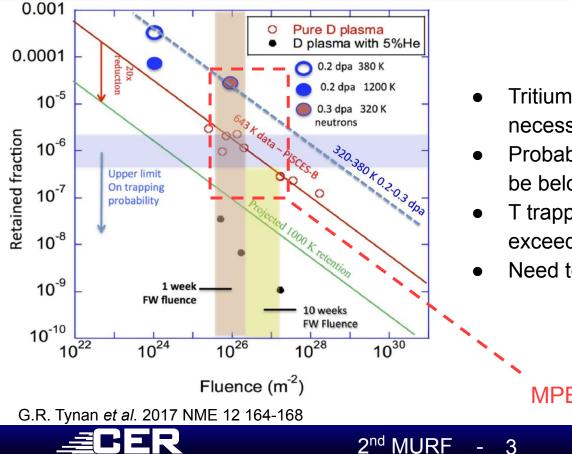
- How to make use of MPEX unique capabilities
 - FPP divertor-like conditions





PISCE:

Very low T retention critical to TBR > 1



Center for Energy Research

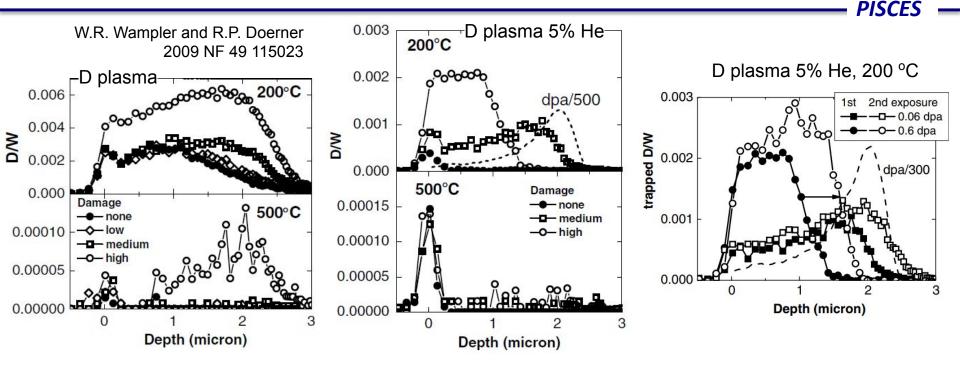
- Tritium Breeding Ratio (*TBR*) above 1 is necessary for viable fusion
- Probability to permanently trap T (p_{trap}) must be below ~10⁻⁶ to have TBR>1
- T trapping in neutron-induced defects can exceed this upper limit
- Need to study retention under FPP conditions

MPEX - systematic study



PISCES

D plasma 5% He significantly reduces D retention



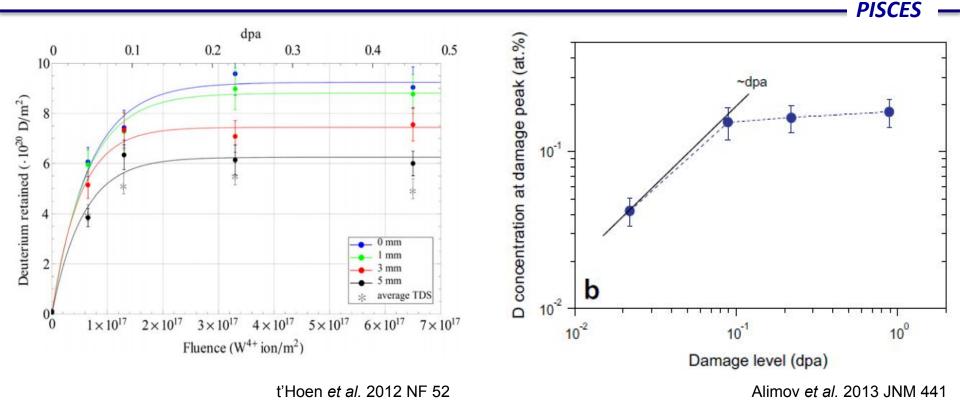
- D plasma with 5% He slows filling of Si-ion damage
- Further study under divertor-like conditions is needed (oblique incidence? detached?)

UC San Diego



 2^{nd} MURF - 4

H retention shown to saturate ~0.2 dpa

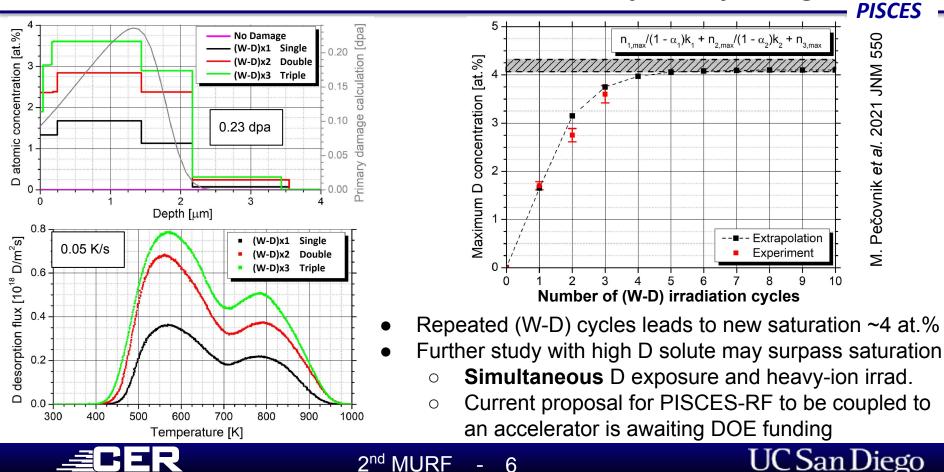








Previous saturation is broken by H synergism

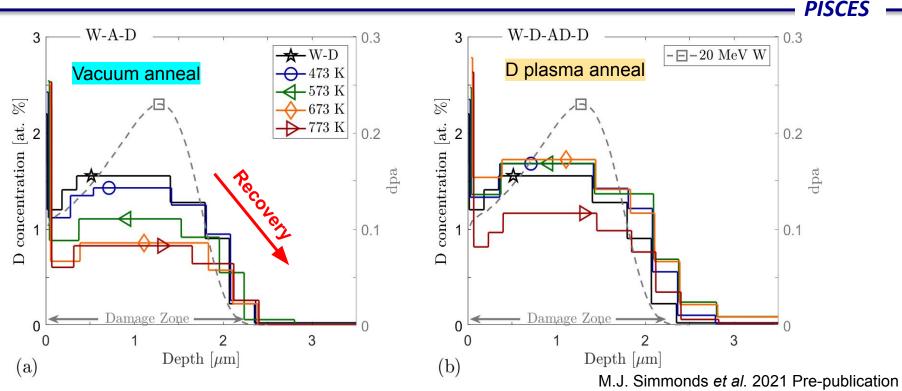


6

2nd MURF



Defect recovery reduced for D plasma anneal



- H present in defects during post-damage annealing reduced recovery



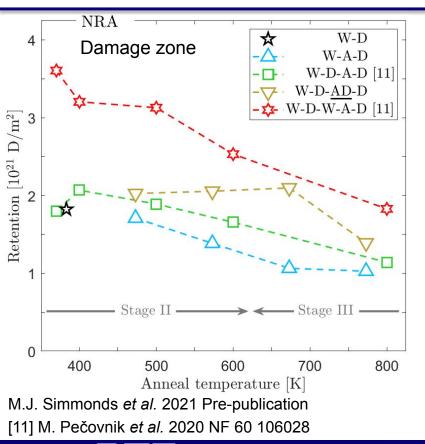
2nd MURF - 7

UC San Diego

Defect annealing/recovery reduced with H present

2nd MURF

8



Retention from lowest to highest:

- **W-A-D** : Vacuum anneal with no D present
- **W-D-A-D** : Vacuum anneal with prev. D exposure
- W-D-<u>AD</u>-D : D plasma exposure during anneal
- W-D-W-A-D : Vacuum anneal with previous D exposure and second W damage
- Clever seq. schemes can still study synergisms without fully simultaneous capabilities



Conclusion

- H retention in heavy-ion damage studies can be performed in collab with smaller facilities
 - Primary diagnostics TGS, NRA, TDS
 - Narrow field of viable W alloys/composites (smaller linear devices)
 - Fill out **FPP relevant** parameter space of retained fraction vs. fluence
 - Perform studies as control/narrow field prior to using n^0 activated material in MPEX
 - Test divertor-like conditions (w/ and w/o detachment)
 - He nano-bubble/fuzz formation (oblique incidence, He%, Temperature?)
 - Repeat with n⁰ damage on same machine for one-to-one comparison
- Experimental schemes utilizing sequential steps may reveal **synergistic** mechanisms
 - If funded, fully simultaneous damage/decoration experiments can guide schemes
 - High H flux may exacerbate synergisms that are H solute dependent (MPEX)
 - Thermal cycling/annealing with high plasma flux (blisters/cracks)





PISCE

Backup Slides







PISCES

Need to study realistic PMI

- Purely sequential and isolated experiments may miss synergies
 - Experiments with **no** H present
 - Heavy-ion damage leads to increased defects until saturation
 - Annealing significantly recovers defects
- Vacancy-interstitial recomb. inhibited when vacancy occupied by H
 - Studied with sequential experimental steps (ensured H present)
 - W damage and H decoration cycles exceeded saturation (T. Schwarz-Selinger*)
 - W damage and H decoration during annealing inhibited recovery (M.J. Simmonds*)
- Material properties under fully simultaneous (FPP-like) conditions?
 - What happens with concurrent damage, decoration, and elevated temperature?
 - Proposal for PISCES-RF to be coupled to an accelerator awaiting DOE funding

*See heavy-ion damage talk tomorrow





PISCE

Heavy-ion damage as proxy for n⁰ damage

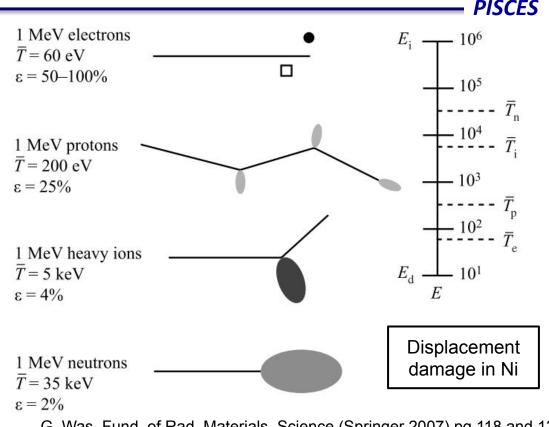
Advantages to heavy-ions

- High dpa rate
 - Short irrad. time
- High ave recoil energy (T)
- Large collision cascade
- No activation of material

Differences

- High dpa rate (too quick)
- Mainly low recoil energy (T)
- Peaked damage (not uniform)
- Near surface (~µm)
- Impurity alloying at high dpa
- No transmutation products

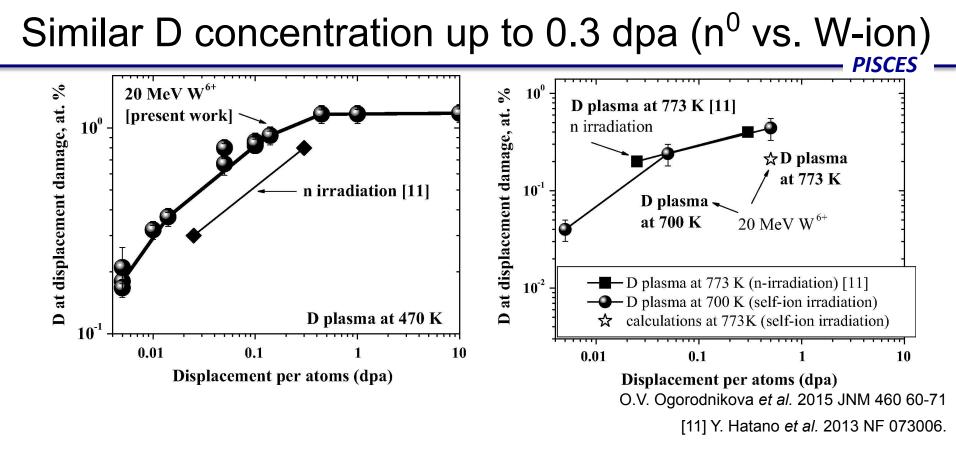




G. Was, Fund. of Rad. Materials Science (Springer 2007) pg.118 and 132

UC San Diego

2nd MURF - 12



• Further study and characterization of n⁰ vs. W-ion damage needed (on same device)

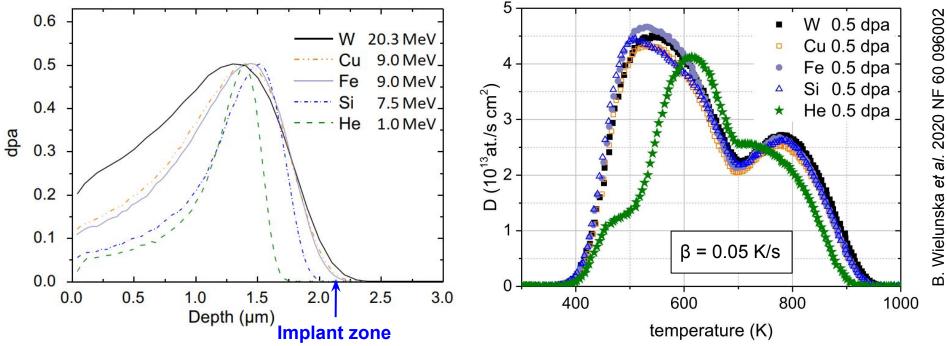
13

2nd MURF



UC San Diego

Mid- to heavy-ion damage similar (below alloying)



- Light-ion damage (i.e. He) creates different concentration of defects
- Damaging ions implanted beyond damage zone (little effect on retention)
- Effect of Re/Ta implantation within the damage zone (varied E) unknown



2nd MURF - 14

UC San Diego